

N-Channel Silicon Carbide Power MOSFET

1. Applications

Asymmetrical Bridge
Converter
Inverter
Single Switch Forward
Flyback

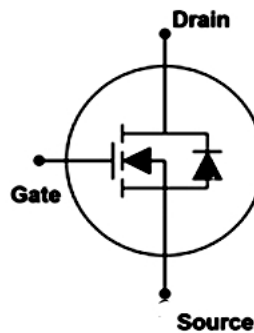
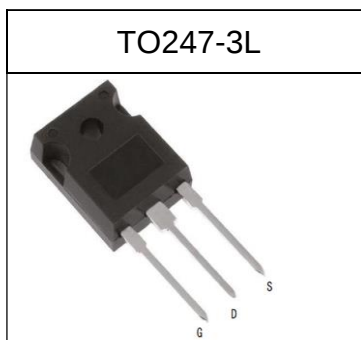
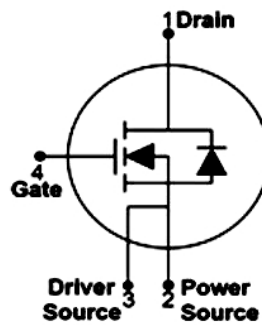
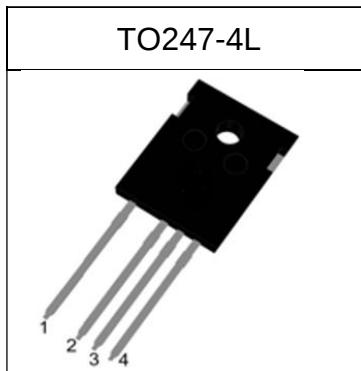
2. Features

Low drain-source on-resistance: $R_{DS(ON)} = 30\text{m}\Omega$ (typ.)
Easy to control Gate switching
Enhancement mode: $V_{th} = 2.2$ to 5V

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_{j,max}$	650	V
$R_{DS(on),max}$	42	$\text{m}\Omega$
$Q_{g,typ}$	97.6	nC
$I_{D,pulse}$	250	A

3. Packaging and Internal Circuit



1 Maximum ratings

at $T_j = 25^{\circ}\text{C}$, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current ¹⁾	I_D	-	-	80	A	$T_C=25^{\circ}\text{C}$
		-	-	58	A	$T_C=100^{\circ}\text{C}$
Avalanche energy, single pulse	E_{AS}	-	-	605	mJ	$T_C=25^{\circ}\text{C}, V_{DD}=50\text{V}, L=10\text{mH}, R_G=25\Omega$
Gate source voltage (dynamic)	V_{GS}	-5	-	20	V	Absolute maximum values
Gate source voltage (static)	V_{GS}	-4	-	18	V	Recommended operational values
Power dissipation	P_{tot}	-	-	294	W	$T_C=25^{\circ}\text{C}$
Storage temperature	T_{stg}	-55	-	175	$^{\circ}\text{C}$	
Operating junction temperature	T_j	-55	-	175	$^{\circ}\text{C}$	
Soldering Temperature Distance of 1.6mm from case for 10s	T_L			260	$^{\circ}\text{C}$	
Transconductance	GFS	-	20.9	-	S	$V_{DS}=20\text{V } I_{DS}=33.5\text{A}$
			21.6			$V_{DS}=20\text{V } I_{DS}=33.5\text{A}, T_j=175^{\circ}\text{C}$

¹⁾ Limited by $T_{j,max}$. Maximum Duty Cycle $D = 0.50$

²⁾ Pulse width t_p limited by $T_{j,max}$

³⁾ Identical low side and high side switch with identical R_G

2 Thermal characteristics

Table 3 Thermal characteristics

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Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	0.51	0.7	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	device on PCB, minimal footprint

3 Electrical characteristics

at $T_j=25^{\circ}\text{C}$, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	650	-	-	V	$V_{GS}=0V$, $I_D=100\mu A$
Gate threshold voltage	$V_{(GS)th}$	2.2	2.8	5.0	V	$V_{DS}=V_{GS}$, $I_D=5mA$
Zero gate voltage drain current	I_{DSS}	-	-	100	μA	$V_{DS}=650V$, $V_{GS}=0V$
Gate-source leakage current	I_{GSS+}	-	-	250	nA	$V_{GS}=20V$, $V_{DS}=0V$
Gate-source leakage current	I_{GSS-}	-	-	-100	nA	$V_{GS}=-5V$, $V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	30	45	$m\Omega$	$V_{GS}=18V$, $I_D=30A$, $T_j=25^{\circ}\text{C}$
		-	33	-		$V_{GS}=18V$, $I_D=30A$, $T_j=150^{\circ}\text{C}$
Gate resistance (Intrinsic)	R_G	-	5.1	-	Ω	$f=1MHz$, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	2333	-	pF	$V_{GS}=0V$, $V_{DS}=400V$, $f=1MHz$
Output capacitance	C_{oss}	-	226.7	-	pF	
Reverse transfer capacitance	C_{rss}	-	12.9	-	pF	
Turn-on delay time	$t_{d(on)}$	-	11.5	-	ns	$V_{DD}=400V$, $I_D=33.5A$, $R_G=2.5\Omega$; $T_j=25^{\circ}\text{C}$ $V_{GS}=-4/18V$ $L=59\mu H$
Rise time	t_r	-	17.5	-	ns	
Turn-off delay time	$t_{d(off)}$	-	32.5	-	ns	
Fall time	t_f	-	8.6	-	ns	
Turn-on Switching Energy	E_{on}	-	71.2	-	μJ	
Turn-off Switching Energy	E_{off}	-	83.9	-	μJ	

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	28.2	-	nC	$V_{DD}=400V$, $I_D=33.5A$, $V_{GS}=-4/18V$
Gate to drain charge	Q_{gd}	-	26.1	-	nC	
Gate charge total	Q_g	-	97.6	-	nC	

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous Source Current	I_{SD}	-	-	80	A	
Diode forward voltage	V_{SD}	-	3.75	-	V	$I_S = 20A$, $V_{GS} = -4V$, $T_J = 25^\circ C$
Reverse recovery time	t_{rr}	-	19.52	-	ns	$V_{GS} = -4V$, $I_{SD} = 33.5A$, $V_R = 400V$ $dif/dt = 1630A/\mu s$, $T_J = 25^\circ C$
Reverse recovery charge	Q_{rr}	-	230	-	nC	
Peak reverse recovery current	I_{rrm}	-	20.44	-	A	
Reverse recovery time	t_{rr}	-	15.04	-	ns	$V_{GS} = -4V$, $I_{SD} = 33.5A$, $V_R = 400V$ $dif/dt = 5665A/\mu s$, $T_J = 25^\circ C$
Reverse recovery charge	Q_{rr}	-	400	-	nC	
Peak reverse recovery current	I_{rrm}	-	46.46	-	A	

4 Electrical characteristics diagram

Diagram 1: Typ. output characteristics

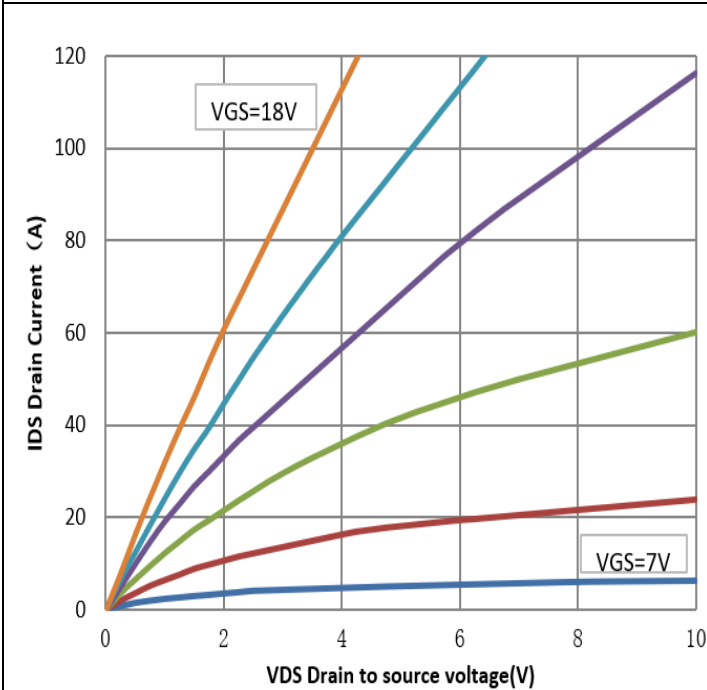

 $I_D = f(V_{DS}); T_J = 25\text{ °C}; \text{parameter: } V_{GS}; V_{GS} = 7, 9, 11, 13, 15, 18\text{V}$

Diagram 2: Typ. output characteristics

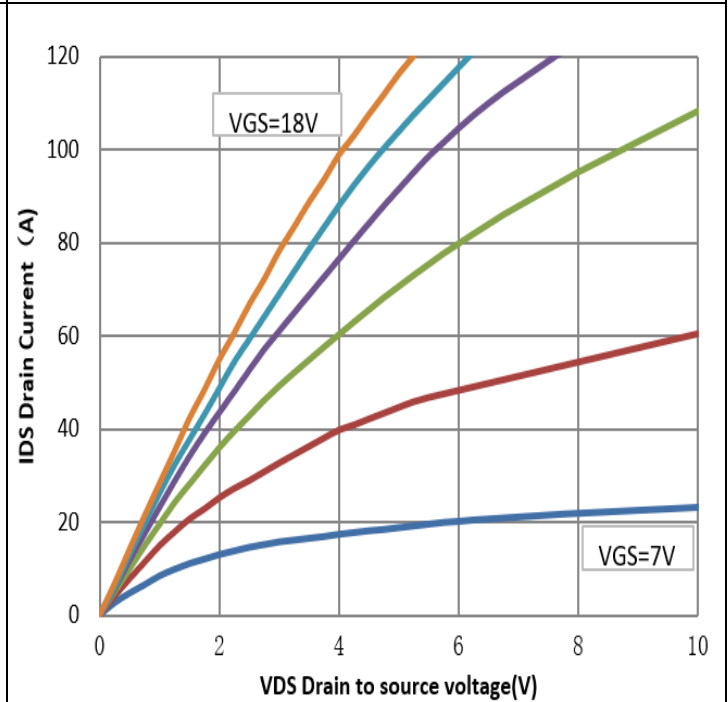

 $I_D = f(V_{DS}); T_J = 175\text{ °C}; \text{parameter: } V_{GS}; V_{GS} = 7, 9, 11, 13, 15, 18\text{V}$

Diagram 3: Typ. transfer characteristics

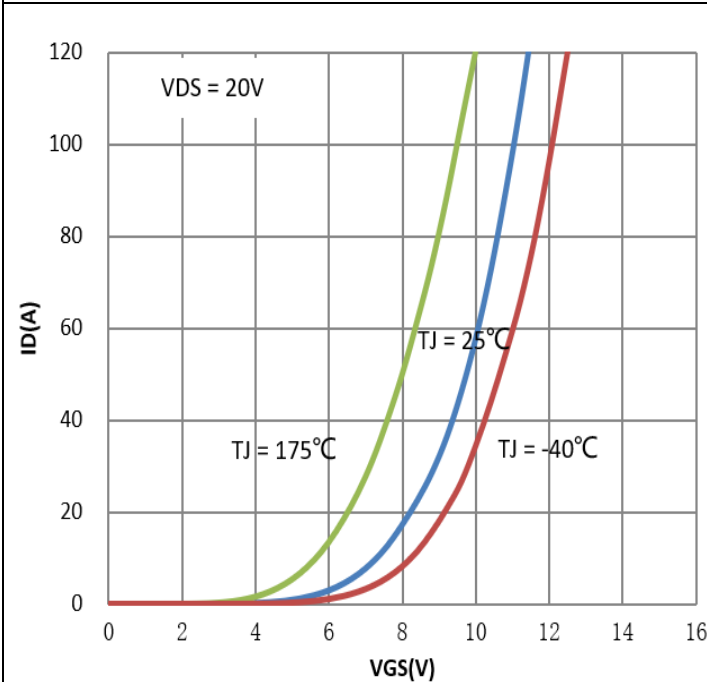

 $I_D = f(V_{GS}); V_{DS} = 20\text{V}; \text{parameter: } T_J$

Diagram 4: Typ. gate charge

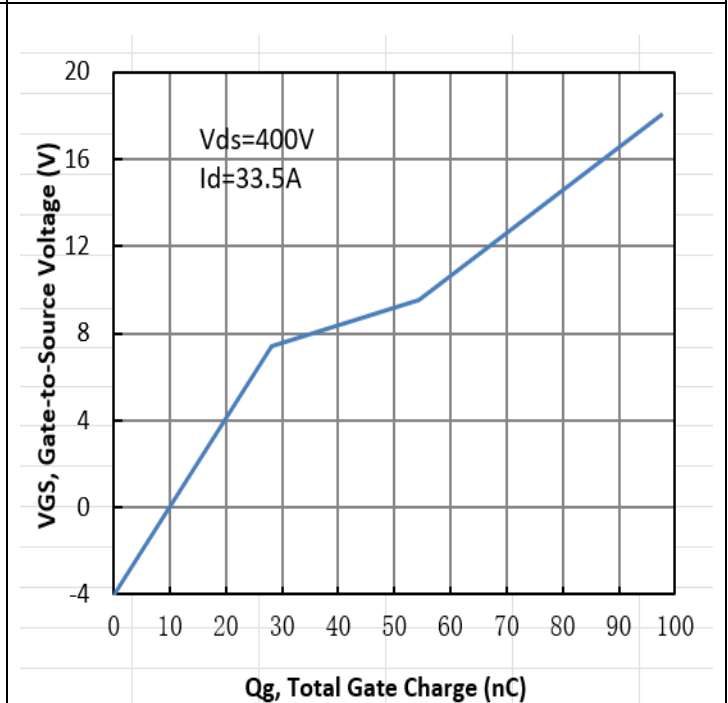
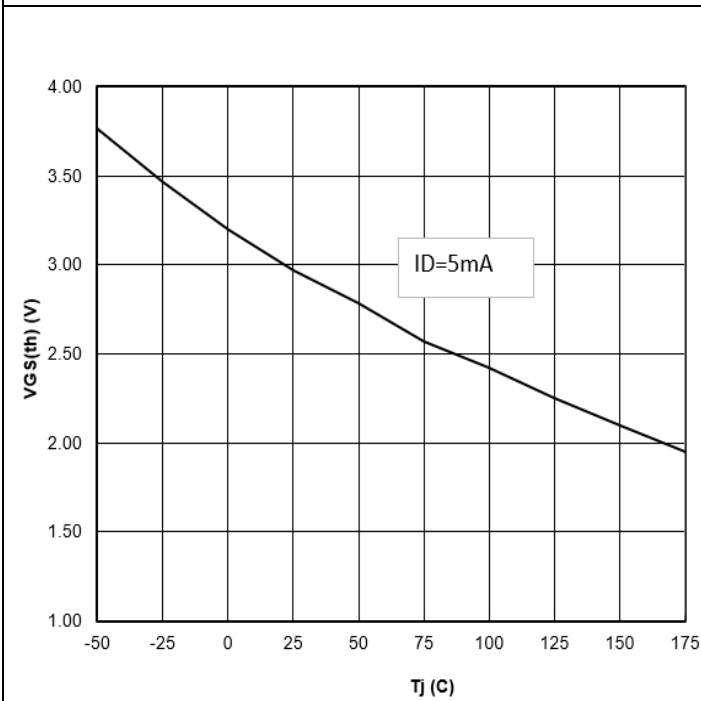
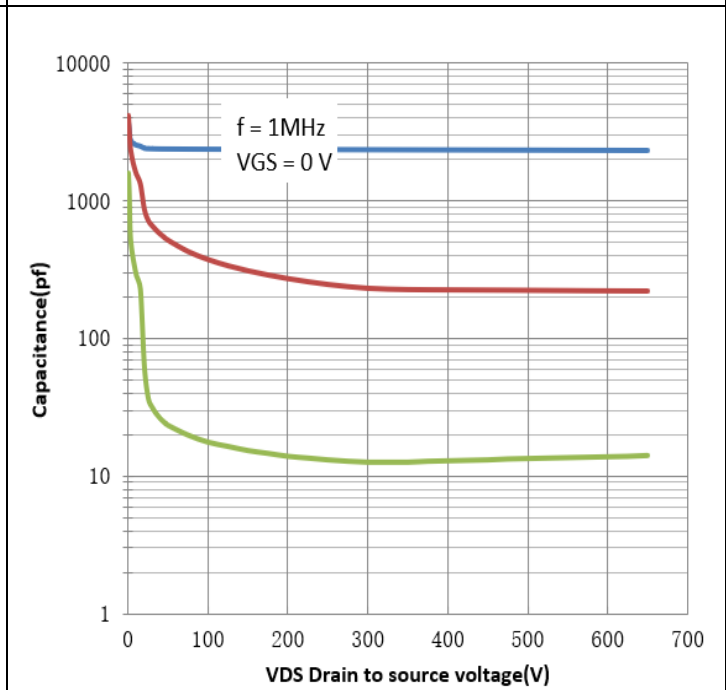

 $V_{GS} = f(Q_{gate}); I_D = 33.5\text{A}; V_{DS} = 400\text{V}; \text{turn-on pulse}$

Diagram 5: Typical gate-source threshold voltage as a function of junction temperature



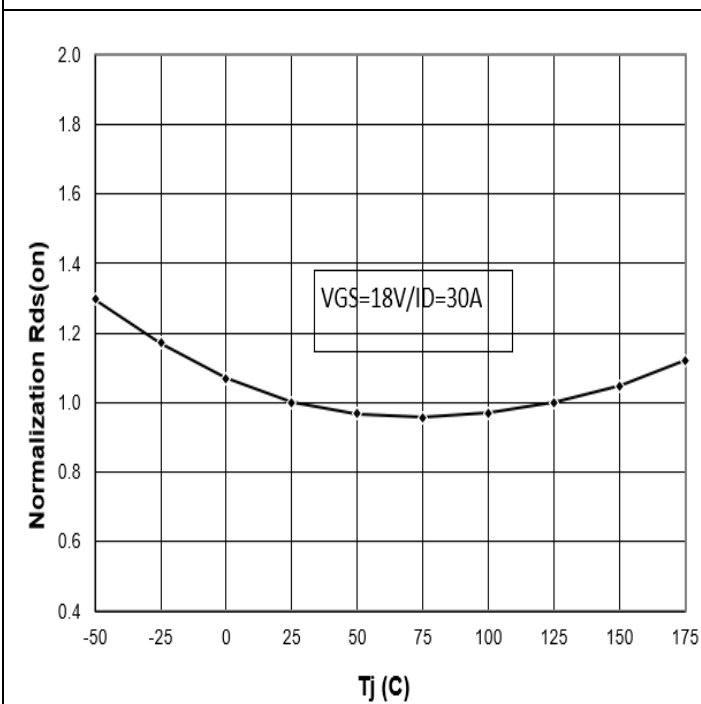
$$V_{GS(th)} = f(T_J); I_{DS} = 5mA; V_{GS} = V_{DS}$$

Diagram 6: Typ. Capacitance as a function of drain-source voltage



$$C = f(V_{DS}); V_{GS} = 0V; f = 1MHz$$

Diagram 7: Normalized on-resistance vs. junction temperature



$$R_{DS(ON)} = f(T_J); I_{DS} = 30A$$

Diagram 8: Typical body diodes Characteristics at 25°C

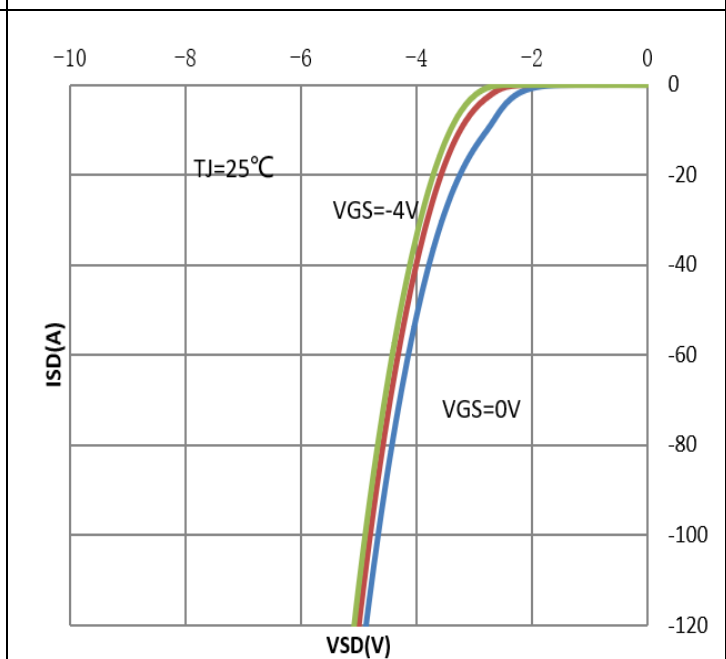
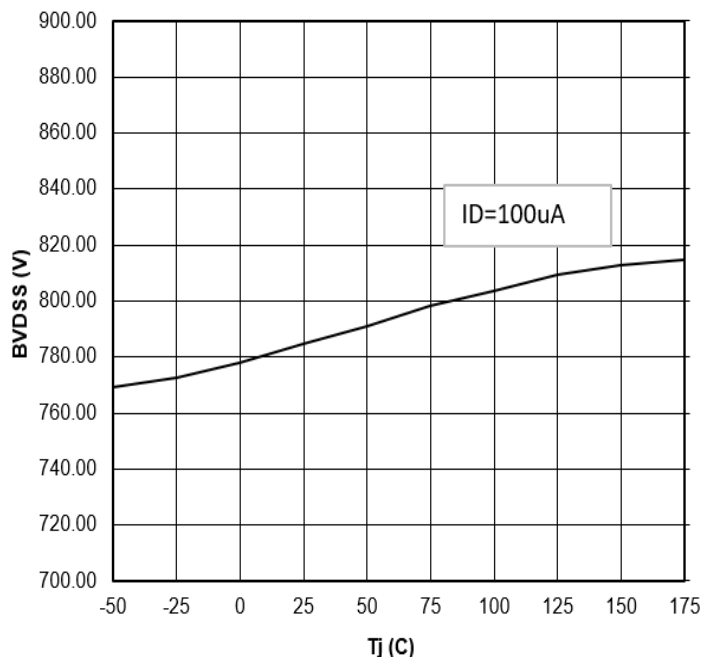
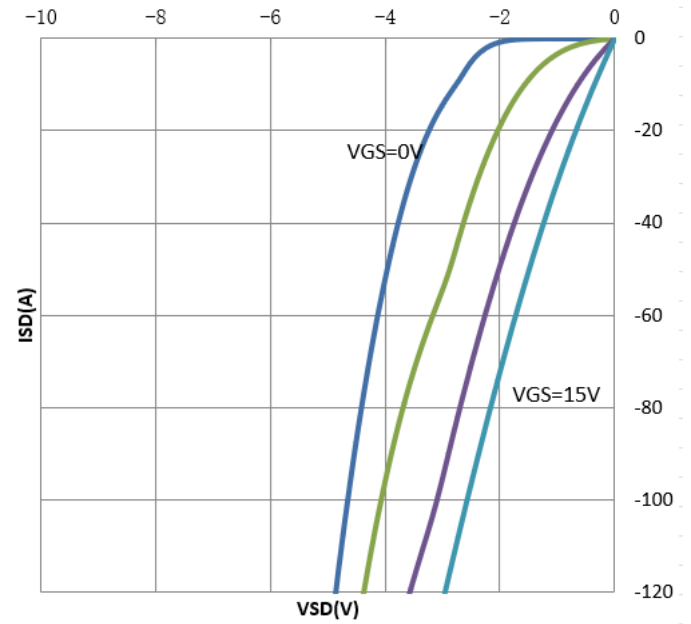


Diagram 9: BVDSS VS junction temperature



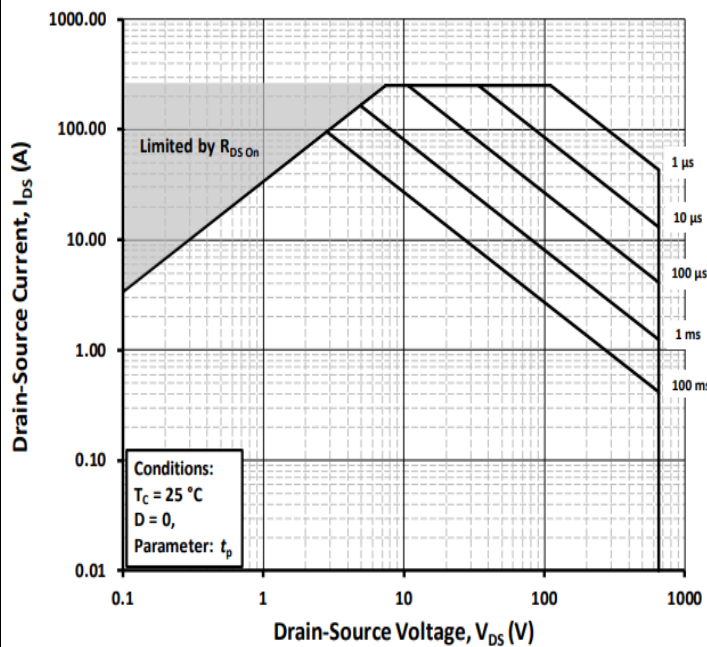
$$Bvdss=f(T_j)$$

Diagram 10: 3rd Quadrant Characteristic at 25 °C



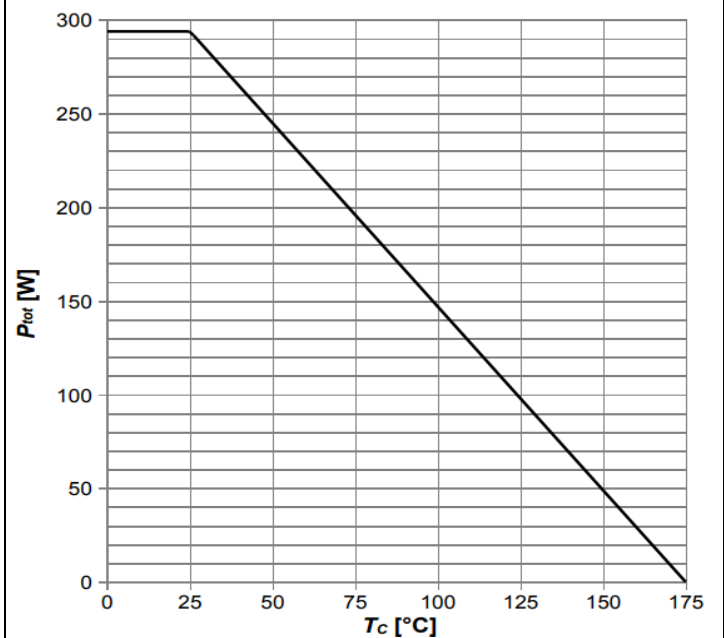
$$I_{SD}=f(V_{SD})$$

Diagram 11: Safe operating area(SOA)



$$V_{GS}=0/18V; T_c=25\text{ }^\circ\text{C}; T_j<175\text{ }^\circ\text{C}$$

Diagram 12: Power dissipation as a function of case temperature limited by bond wire



$$P_{tot}=f(T_c)$$

Diagram 13: Clamped Inductive Switching Energy vs. Drain Current (VDD = 400V)

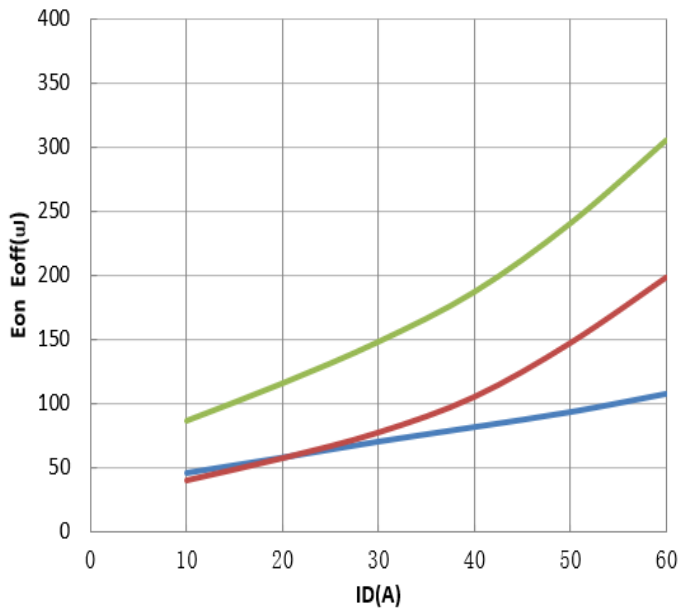


Diagram 14: Clamped Inductive Switching Energy vs. RG(ext)

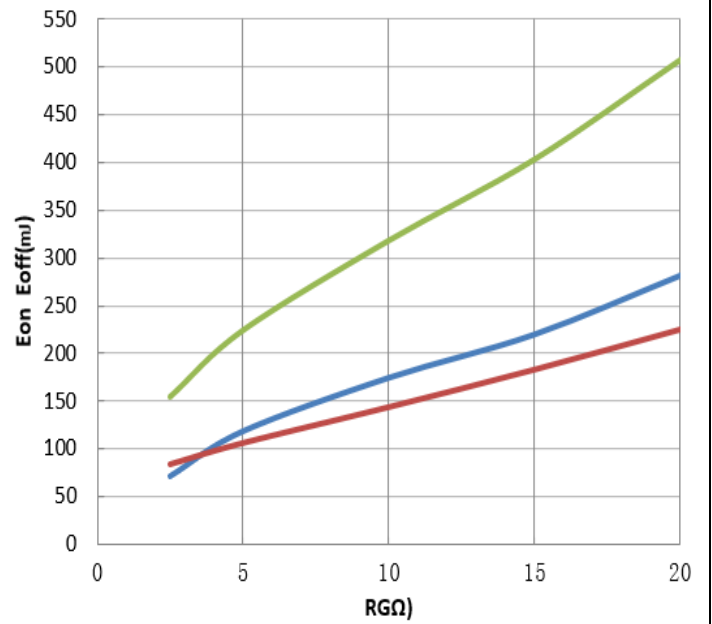


Diagram 15: Clamped Inductive Switching Energy vs. Temperature

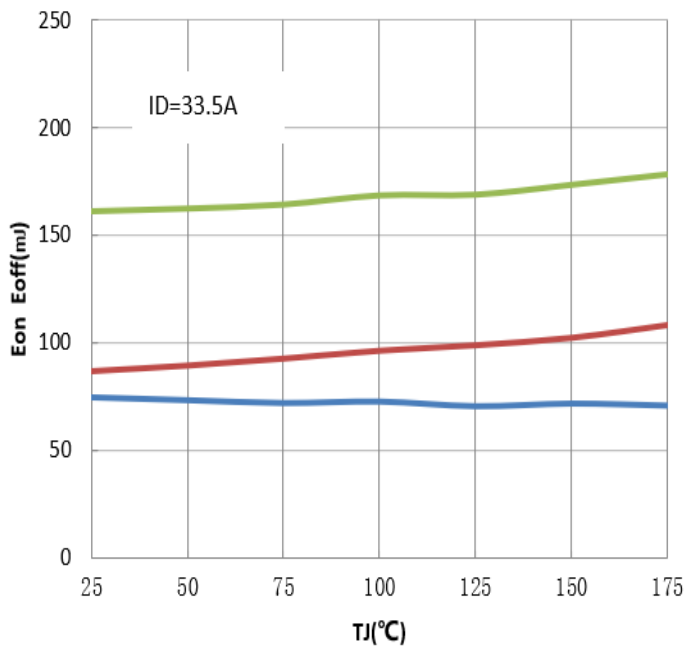


Diagram 16: Switching Times vs. RG(ext)

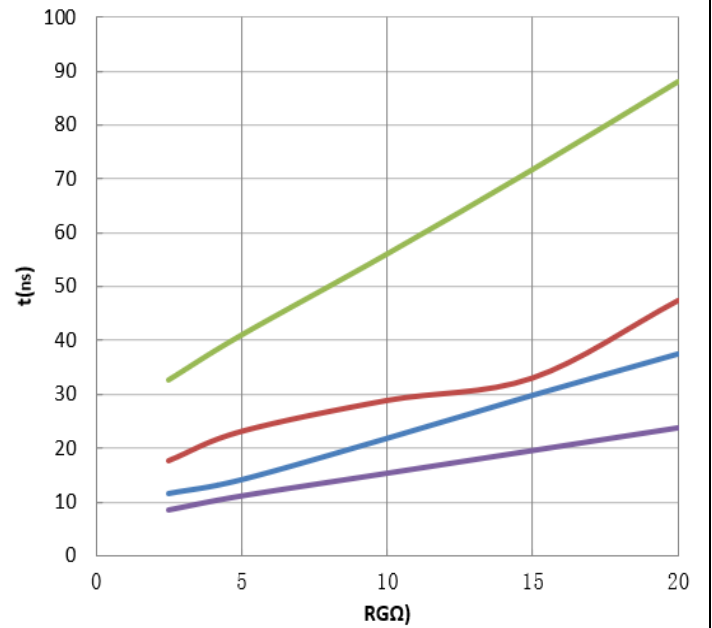
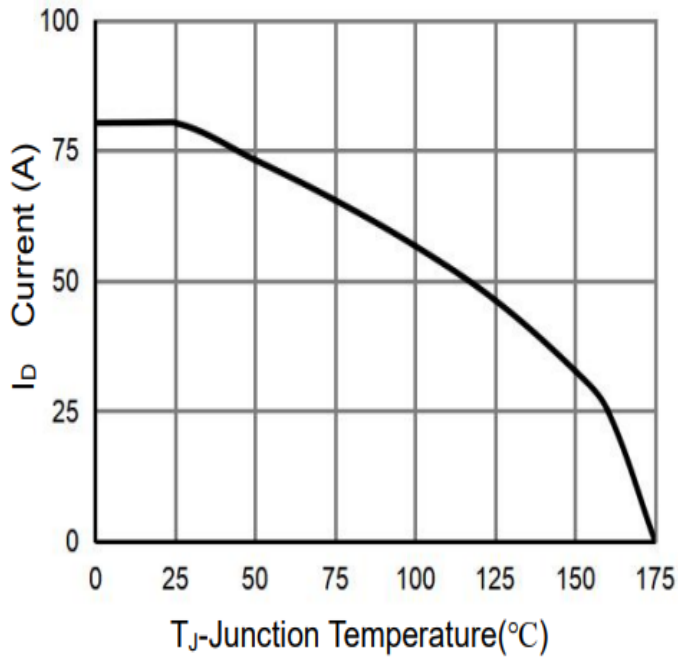
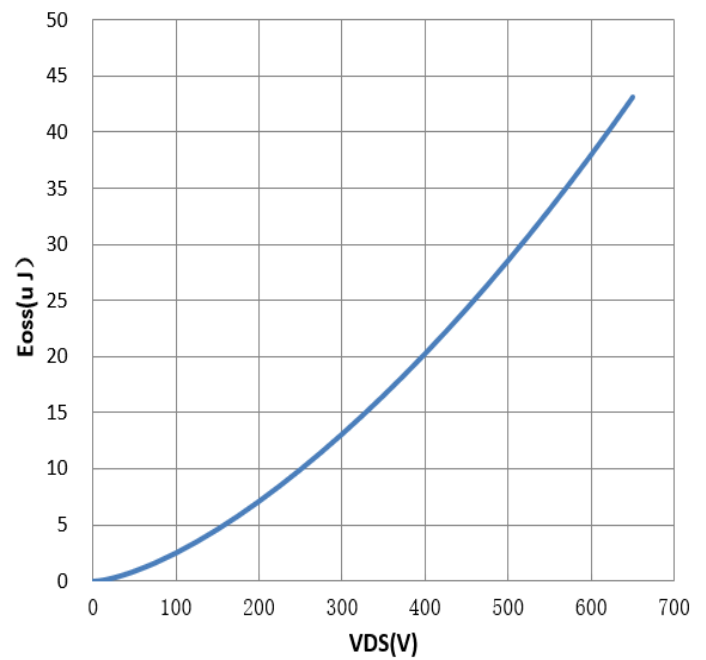


Diagram 17: Continuous Drian Current Derating vs. Case Temperature



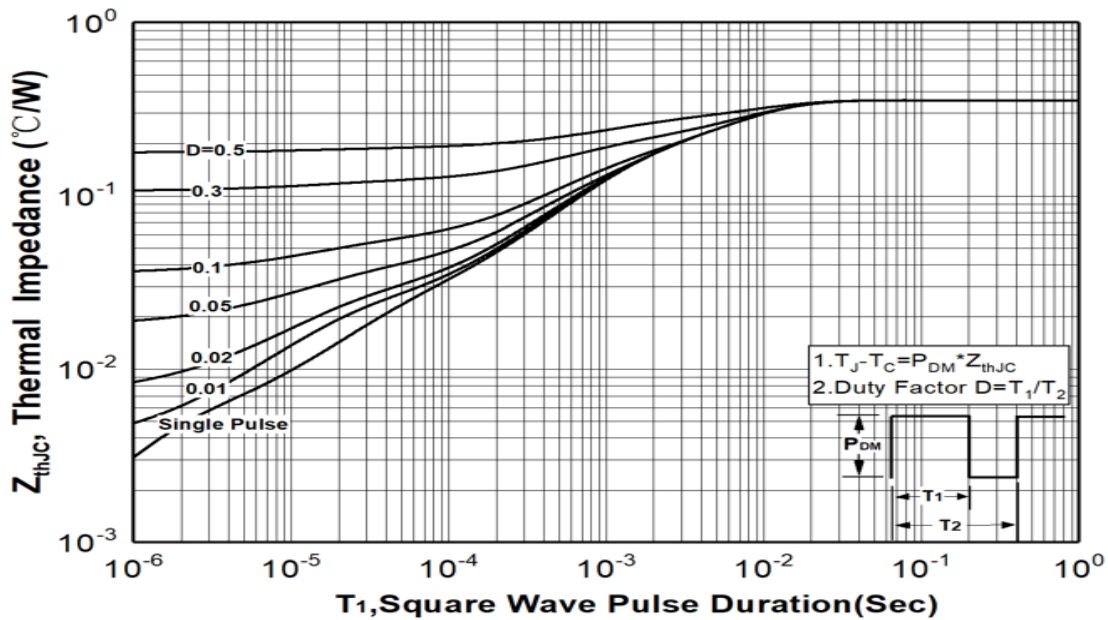
$$I_{DS} = f(T_C)$$

Diagram 18: Output Capacitor Stored Energy



$$E_{oss} = f(V_{DS})$$

Diagram 19: Max. transient thermal resistance(MOSFET/diodes)



$$Z_{th(j-c,max)} = f(t_p), \text{parameter } D = t_p / T$$

5 Test Circuits

Table 8 Diode characteristics

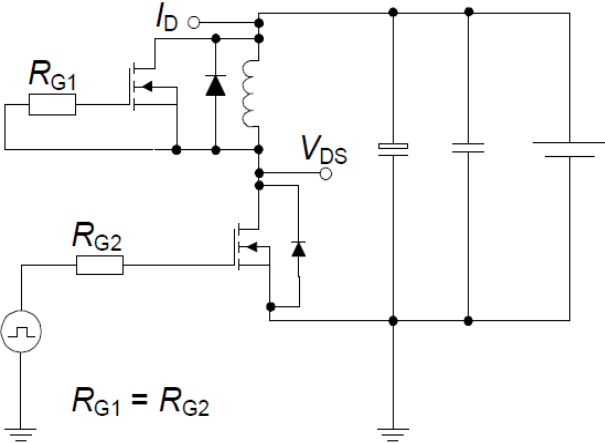
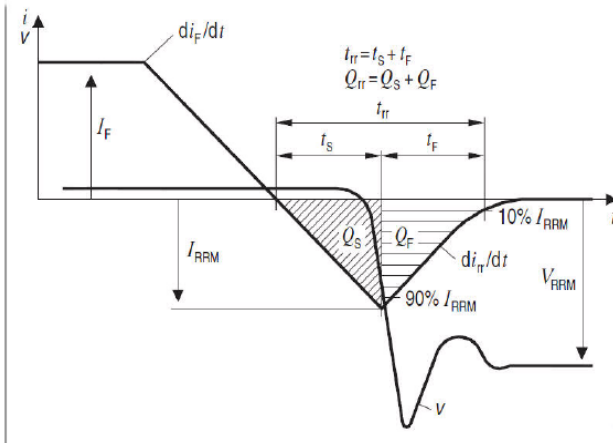
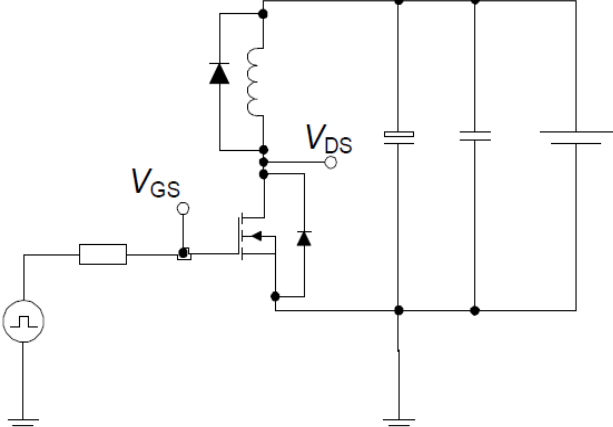
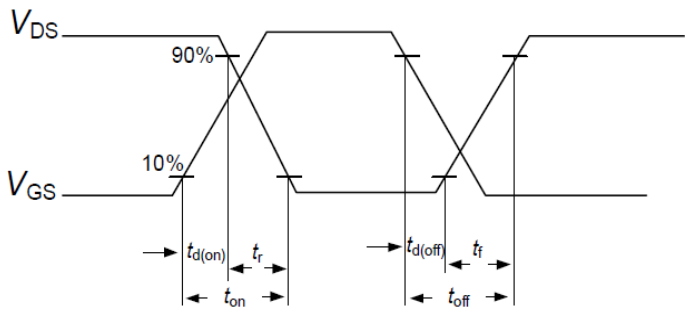
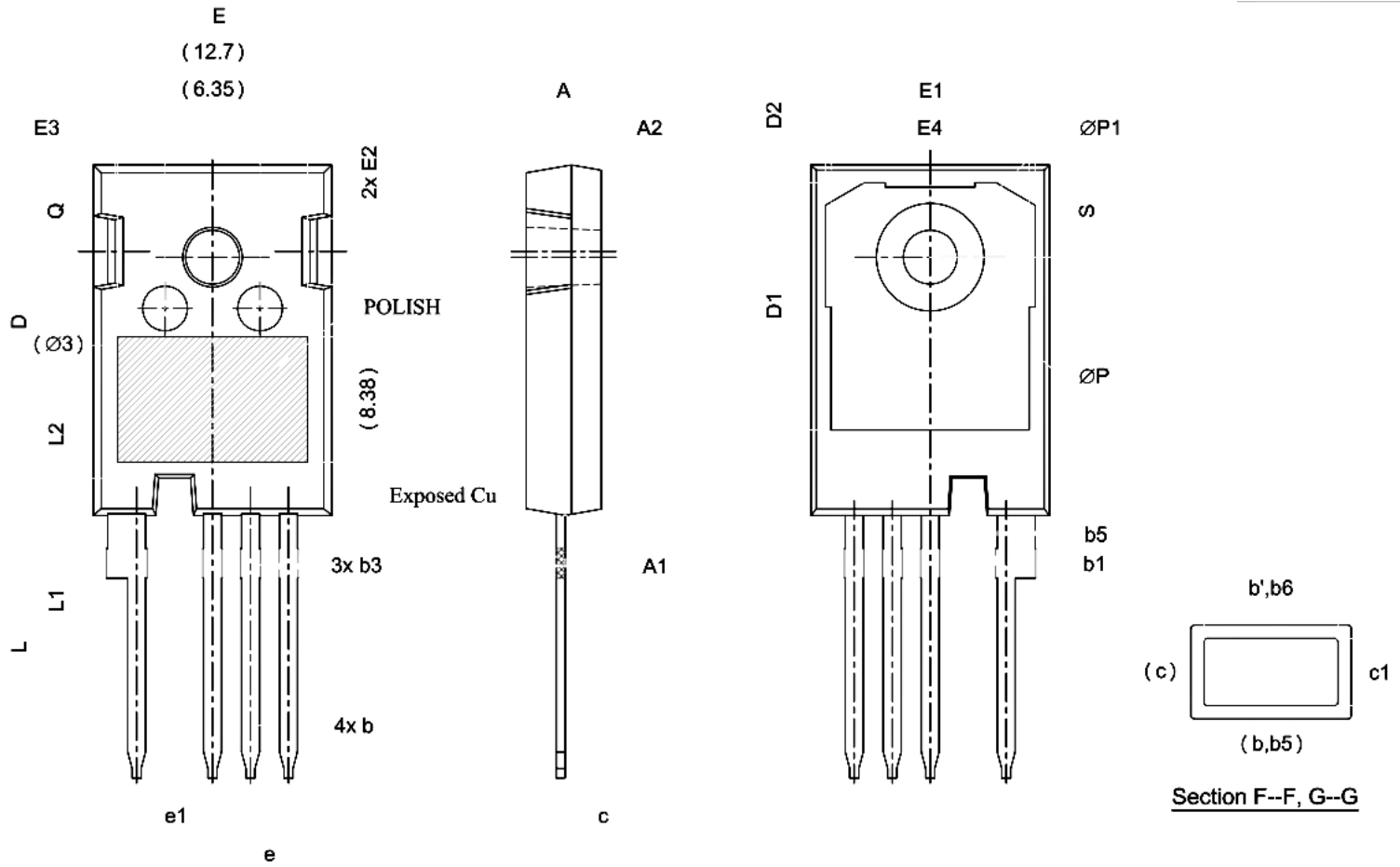
Test circuit for diode characteristics	Diode recovery waveform
 $R_{G1} = R_{G2}$	

Table 9 Switching times

Switching times test circuit for inductive load	Switching times waveform
	

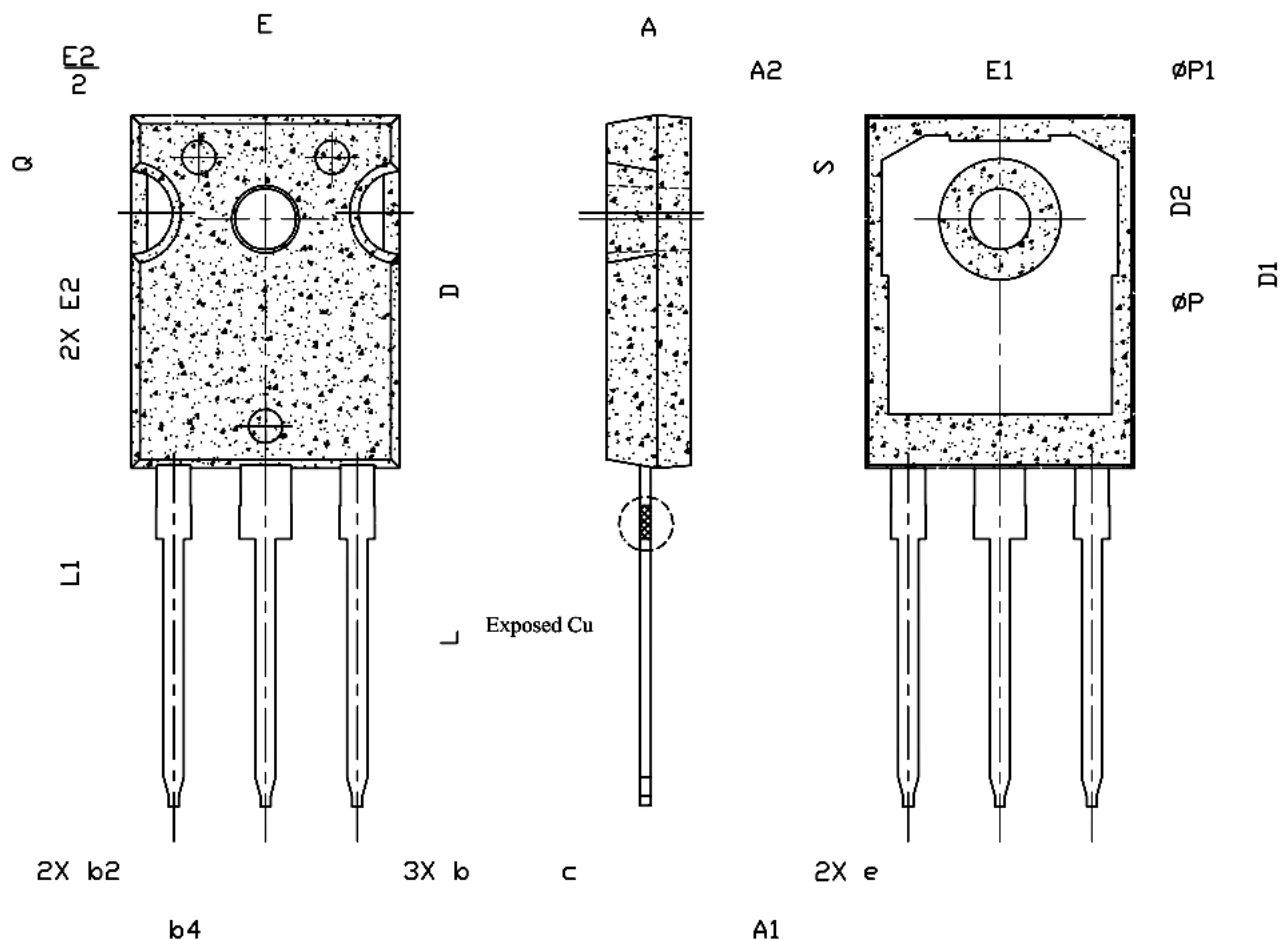
6 Package Outlines

TO-247-4L



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	4.83	5.02	5.21
A1	2.29	2.41	2.54
A2	1.91	2.00	2.16
b'	1.07	1.20	1.28
b	1.07	1.20	1.33
b1	2.39	2.67	2.94
b3	1.07	1.30	1.60
b5	2.39	2.53	2.69
b6	2.39	2.53	2.64
c	0.55	0.60	0.68
c1	0.55	0.60	0.65
D	23.30	23.45	23.60
D1	16.25	16.55	17.65
D2	0.95	1.19	1.25
E	15.75	15.94	16.13
E1	13.10	14.02	14.15
E2	3.68	4.40	5.10
E3	1.00	1.45	1.90
E4	12.38	13.26	13.43
e	2.54 BSC		
e1	5.08 BSC		
L	17.31	17.57	17.82
L1	3.97	4.19	4.37
L2	2.35	2.50	2.65
ØP	3.51	3.61	3.65
ØP1	7.19 REF.		
Q	5.49	5.79	6.00
S	6.04	6.17	6.30

TO-247-3L



SYMBOL	DIMENSIONS			NOTES
	MIN.	NOM.	MAX.	
A	4.83	5.02	5.21	
A1	2.29	2.41	2.55	
A2	1.50	2.00	2.49	
b	1.12	1.20	1.33	
b1	1.12	1.20	1.28	
b2	1.91	2.00	2.39	6
b3	1.91	2.00	2.34	
b4	2.87	3.00	3.22	6, 8
b5	2.87	3.00	3.18	
c	0.55	0.60	0.69	6
c1	0.55	0.60	0.65	
D	20.80	20.95	21.10	4
D1	16.25	16.55	17.65	5
D2	0.51	1.19	1.35	
E	15.75	15.94	16.13	4
E1	13.46	14.02	14.16	5
E2	4.32	4.91	5.49	3
e	5.44BSC			
L	19.81	20.07	20.32	
L1	4.10	4.19	4.40	6
ϕP	3.56	3.61	3.65	7
$\phi P1$	7.19REF.			
Q	5.39	5.79	6.20	
S	6.04	6.17	6.30	